# FISCHERSCOPE® X-RAY XAN® 220

X-Ray Fluorescence Measuring Instrument for fast and non-destructive Analysis and Coating Thickness Measurement of Gold and Silver Alloys





# FISCHERSCOPE® X-RAY XAN® 220

#### **Main Features**

The FISCHERSCOPE X-RAY XAN 220 is an optimized X-ray fluorescence measuring instrument for non-destructive analysis of jewelry, coins and precious metals.

It is particularly suited for the analysis of precious metals and their alloys in composition and coating thickness. Up to 24 elements in the range of Chlorine (17) to Uranium (92) can be determined simultaneously.

Typical fields of application are the analysis of:

- · Jewelry, precious metals and dental alloys
- · Yellow and white gold
- Platinum and silver
- Rhodium
- · Alloys and coatings
- · Multi layer coatings

Outstanding accuracy and long-term stability are characteristics of all FISCHERSCOPE X-RAY systems. The necessity of recalibration is dramatically reduced, saving time and effort.

The modern silicon drift detector achieves high accuracy and good detection sensitivity.

The fundamental parameter method by Fischer allows for the analysis of solid and liquid specimens as well as coating systems without calibration.

#### Design

The XAN 220 is designed as a user-friendly bench-top instrument.

Specimen positioning is quick and easy. The X-ray source and semiconductor detector assembly is located in the instrument's lower chamber, so that the measuring direction is from underneath the sample, which is supported by a transparent window.

The integrated video-microscope with zoom and crosshairs simplifies sample placement and allows precise measuring spot adjustment.

The entire operation and evaluation of measurements as well as the clear presentation of measurement data is performed on a PC, using the powerful and user-friendly  $WinFTM^{\textcircled{8}}$  software.

The FISCHERSCOPE X-RAY XAN 220 fulfills DIN ISO 3497 and ASTM B 568.

# **General Specification**

Intended use Energy dispersive X-ray measuring instrument (EDXRF) to analyze precious metals

and their alloys in composition and coating thickness.

Element range Chlorine (17) to Uranium U (92) – up to 24 elements simultaneously

Repeatability ≤ 0,5 % for gold, measurement time 60 sec

Design Bench top unit with upwards opening hood

Measurement direction From bottom to top

## X-Ray Source

X-ray tube Micro focus tube with tungsten target and beryllium window

High voltage Three steps: 30 kV, 40 kV, 50 kV

Aperture (Collimator) Ø 1 mm (39 mils), optional Ø 2 mm (79 mils)

Measurement spot Aperture diameter plus 200 µm (8 mils), at measurement distance MD = 0 mm

### X-Ray Detection

X-ray detector Silicon Drift Detector (SDD), peltier-cooled

Resolution (fwhm for Mn- $K_{cr}$ )  $\leq 160 \text{ eV}$ 

Measuring distance 0 ... 10 mm (0 ... 0.4 in)

Distance compensation with patented DCM method for simplified measurements at varying distances. For particular applications an additional calibration might be

necessary.

# **Sample Alignment**

Sample positioning Manually

High-resolution CCD color camera for optical monitoring of the measurement loca-

tion along the primary beam axis,

Crosshairs with a calibrated scale (ruler) and spot-indicator, Adjustable LED illumination of the measurement location

Zoom factor Digital 1x, 2x, 3x, 4x

#### **Sample Stage**

Design Fixed sample support

Usable sample placement area 310 x 320 mm (12.2 ... 12.6 in)

Max. sample weight 2 kg (4.4 lb)

Max. sample height 90 mm (3.5 in)

#### **Electrical Data**

Power supply AC 115 V or AC 230 V 50 / 60 Hz Power consumption max. 120 W, without evaluation PC

Protection class IP40

#### **Dimensions**

External dimensions Width x depth x height [mm]: 403 x 588 x 365 mm, [in]: 15.9 x 23.1 x 14.4

Weight approx. 45 kg (99 lb)

#### **Environmental Conditions**

10 °C - 40 °C (50 °F - 104 °F) Operating temperature Storage temperature 0 °C - 50 °C (32 °F - 122 °F) Admissible air humidity ≤ 95 %, non-condensing

#### **Evaluation Unit**

Windows®-PC Computer

Standard: Fischer WinFTM® BASIC including PDM® Software

Optional: Fischer WinFTM® SUPER

#### **Standards**

FN 61010 CE approval

X-Ray standards DIN ISO 3497 and ASTM B 568

Approval Individual acceptance inspection as a fully protected instrument according to the

German regulations "Deutsche Röntgenverordnung-RöV". Type approval requested.

#### Order

FISCHERSCOPE X-RAY XAN220 604-771

Special XAN product modification and XAN technical consultation on request

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